

# Linearity and Intrinsic Gain Enhancement Techniques using Positive Feedbacks to Realize a 1.2-V, 200-MHz, +10.3-dBm of IIP3 and 7th-order LPF in a 65-nm CMOS

Yasuhiro Sugimoto

Department of Electrical, Electronic and Communication Engineering, Chuo University  
1-13-27, Kasuga, Bunkyo-ku, Tokyo 112-8551, Japan  
Tel: +81338171858, Fax: +81338171846, Email: sugimoto@sugi.elect.chuo-u.ac.jp

**Abstract**—Linearity and intrinsic gain enhancement techniques for realizing high-performance and low-voltage analog circuits in a deep-submicron CMOS are introduced. In place of a differential amplifier for the voltage-to-current (V/I) conversion at the input, a V/I conversion using a linear resistor and a positive feedback in a pseudo-differential configuration was adopted. The positive feedback concept was also applied to enhance the intrinsic gain of the deep-submicron MOS transistor which is used as a current source to realize high output impedance in amplifiers. In order to verify the effectiveness of the proposed techniques, a MOS 7th-order Gm-C linear phase low-pass-filter (LPF) was realized using a 65-nm CMOS process. Evaluation results showed that the -3 dB frequency bandwidth, group delay ripple, 3rd-order distortion and 3rd-order input intercept point (IIP3) were 200 MHz, 2.2%, less than -55 dB with a 100-MHz input and +10.3 dBm, respectively, all with a  $\pm 0.1$  Vp-p signal input at each input terminal in pseudo differential configuration, while the LPF including an output buffer dissipated 60 mW from a 1.2-V supply.

## I. INTRODUCTION

The gate-leak problem and low supply-voltage operation are dominant obstacles for LSI circuits in deep-submicron CMOS processes [1]. However, the gate-leak problem can be avoided if the voltage applied to the transistor is suppressed as low as 1 V; this in turn introduces the low-voltage-operation issue. However, low-supply-voltage operation is hard for on-chip high-performance analog circuits because they suffer from extensive dynamic range reduction. Another serious problem in analog circuits is that the intrinsic gain ( $g_m/g_{ds}$ ), assuming the threshold voltage is kept constant, becomes very low in a deep-submicron transistor and the linearity degrades significantly in an amplifier.

To overcome these drawbacks, we propose the use of a linear resistor with applied positive feedback to convert the input signal voltage into current at the amplifier's input, instead of using a conventional differential circuit. The configuration in pseudo-differential form provides good linearity of the converted differential signal current under low-supply-voltage conditions. We further propose the use of positive feedback to increase the output impedance of a cascode current source at the output part of an amplifier. The high output impedance of

the current source leads to high voltage gain and high linearity in a low-voltage amplifier. As a result, a low-voltage and high-performance transconductance amplifier could be realized. In order to verify the effectiveness of our proposal, a 7th-order Gm-C linear phase filter in a 65-nm CMOS process was fabricated. A new filter block configuration for a differential second-order LPF was developed and adopted. To compensate for the process, voltage and temperature (PVT) variation of transistors, capacitors and resistors, the programmability of the capacitors and resistors by the external control signal was ensured.

## II. TRANSCONDUCTANCE AMPLIFIER DESIGN

In our filter, two transconductance amplifiers were used to form a second-order LPF. We designed the input part of the transconductance amplifier to realize 1.2-V operation, a -3 dB frequency bandwidth of 12 GHz and a THD of -68 dB with a  $\pm 0.1$  Vp-p input at 100 MHz at each input terminal in pseudo differential configuration by simply carrying out the input V/I conversion using a linear resistor, positive feedback and a common gate transistor, as shown in Figure 1(a). We have already proposed the same type of linearity enhancement

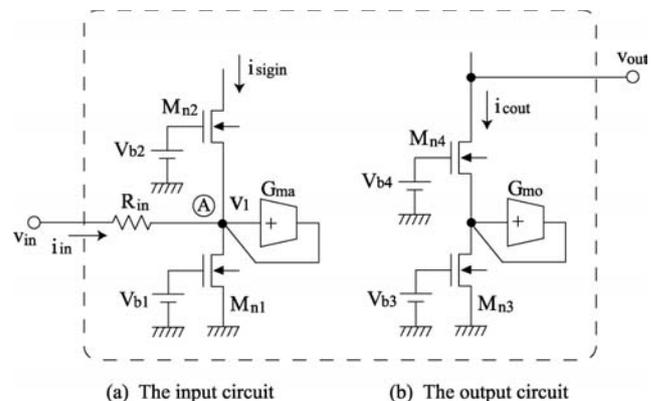


Fig. 1. Transconductance amplifier circuit. (a) Transconductance is linearized at the input. (b) Impedance is increased at the output.



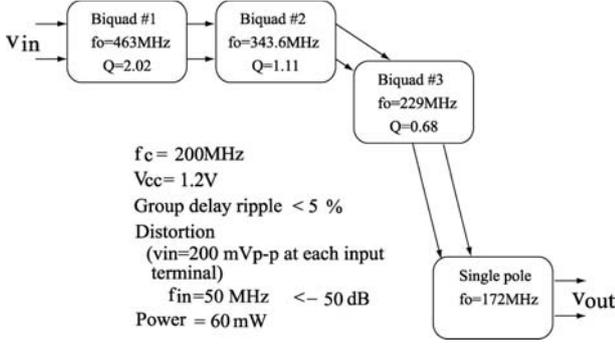


Fig. 3. Block diagram of the targeted 7th-order linear phase LPF.

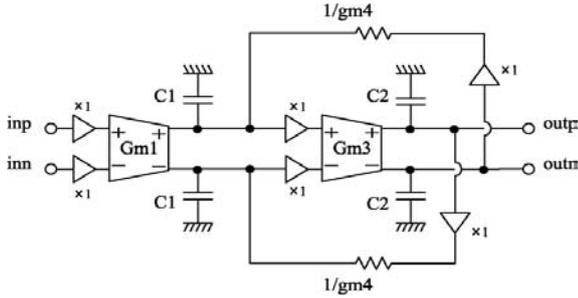


Fig. 4. The developed configuration of the 2nd-order LPF.

to form a Biquad LPF. In contrast to this previous design, we introduced a simplified Biquad LPF by replacing the transconductors with resistors, as shown in Figure 4. Note that we needed to put triangular-shaped buffers to drive and supply enough current to the resistor. However, we still obtained a small element count and a larger phase margin than in the previous design by eliminating complex transconductor amplifiers. Providing that the gain of the triangular-shaped buffer is unity, then the transfer function  $H(s)$ , the dc voltage gain  $A_0$ , natural frequency  $\omega_0$ , and Q factor in this new configuration becomes

$$H(s) = \frac{G_{m1}}{g_{m4}} \cdot \frac{\frac{G_{m3}g_{m4}}{C_2C_1}}{s^2 + \frac{g_{m4}}{C_1}s + \frac{G_{m3}g_{m4}}{C_2C_1}}$$

$$A_0 = \frac{G_{m1}}{g_{m4}}, \quad \omega_0 = \sqrt{\frac{G_{m3}g_{m4}}{C_1C_2}}, \quad Q = \sqrt{\frac{G_{m3}C_1}{g_{m4}C_2}} \quad (3)$$

Equation (3) indicates that  $A_0$  and Q do not change even when the values of  $g_{m4}$ ,  $G_{m1}$  and  $G_{m3}$  change due to the PVT variation because all of their values are decided by resistors that have the same variation characteristic, while  $\omega_0$  does change due to the lack of the tracking capability between a transconductance and a capacitor. The adjustment capability of capacitors  $C_1$  and  $C_2$  and a resistor  $1/g_{m4}$  is provided by selecting one resistor out of several feedback resistors in parallel and connecting small capacitors in parallel using MOS switches controlled by an external signal.

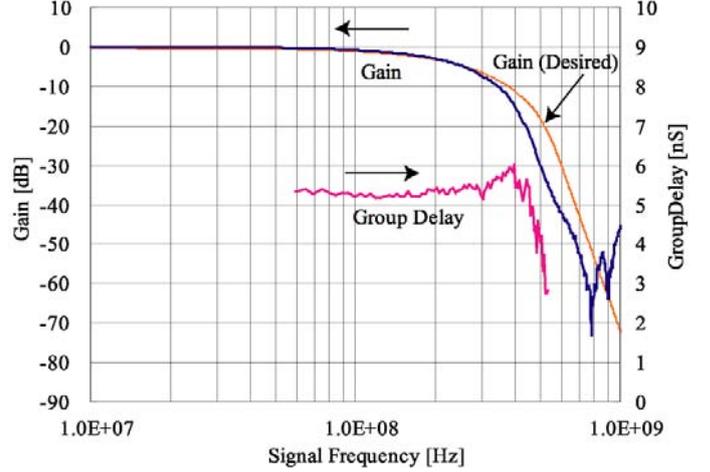


Fig. 5. Frequency characteristics and the group delay of the 7th-order LPF.

#### IV. EXPERIMENTAL RESULTS

The 7th-order LPF shown in Figure 3 was designed, fabricated and evaluated using 65-nm CMOS devices. The drain-to-source resistance of a transistor with the gate length and gate width of 65 nm and 19.5  $\mu\text{m}$ , respectively, was simulated to be 1.5 k $\Omega$  when the drain-to-source voltage was 0.25 V in the saturation region. The power dissipation of this 7th-order LPF was 60 mW, which includes output buffers from a 1.2-V supply. The core chip size was 0.5 mm $\times$ 0.7 mm.

Figure 5 shows the measured frequency characteristics of the voltage gain and group delay of the 7th-order linear phase LPF. The corner frequency,  $f_c$ , was 200 MHz and the gain characteristics agreed well with the theoretical value up to 300 MHz. The group delay ripple was calculated to be 2.2% by using the formula

$$\text{Group Delay Ripple} = \frac{\text{Max}[\tau(f)] - \text{Min}[\tau(f)]}{\text{Max}[\tau(f)] + \text{Min}[\tau(f)]} \quad (4)$$

where Max and Min are the maximum and minimum values of the group delay  $\tau(f)$  in the frequency range from  $0.3f_c$  to  $f_c$  [7].

Figure 6 displays the frequency spectrum up to 500 MHz when a  $\pm 100$  mVp-p and a 100-MHz input signal was applied at each input terminal of the 7th-order linear phase LPF. As the filter is configured in pseudo differential form, the input signal level is considered equivalent to be  $\pm 200$  mVp-p. As described in section II, the even-order harmonics were suppressed not in the transconductance amplifier but in the pseudo-differential configuration. The second harmonic can not be fully attenuated only by the pseudo-differential configuration. It was observed to be -51.88 dB relative to the output signal and was the largest in harmonics. The incompleteness of the common-mode feedback in a transconductor amplifier may produce even-order harmonics. In contrast, a very low third harmonic below -55 dB was obtained.

Figure 7 shows the result of the two-tone inter-modulation test using 99-MHz and 101-MHz input signals. The input

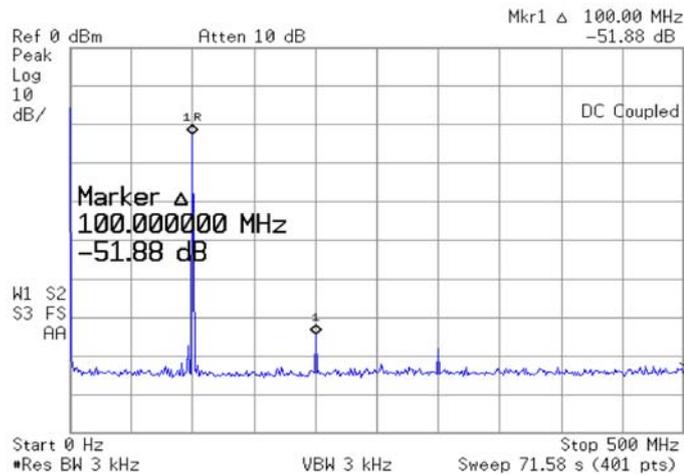


Fig. 6. The frequency spectrum up to 500 MHz with a full-scale 100-MHz signal input.

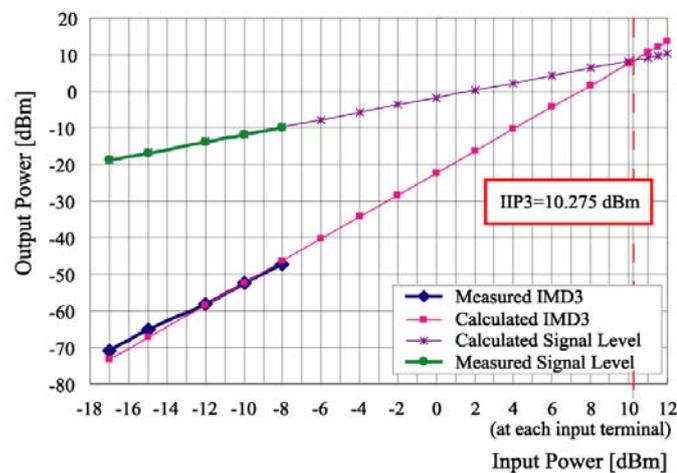


Fig. 7. The 3rd-order input intercept point ( $f_{in1}=99$  MHz,  $f_{in2}=101$  MHz).

power is the sum of the power of two signals. When the sum of two signal powers was set to -10 dBm at each input terminal in pseudo differential configuration, which is the full-scale input signal power at each input terminal, the measured 3rd-order distortion was -40.17 dB. The calculated IIP3 value became +10.3 dBm. If we take differential signals into account, it becomes equivalent to be +16.3 dBm. This large IIP3 value also meant that a highly linear operation was achieved under the condition of being forced to tolerate very low output resistance of a transistor and a low supply voltage of 1.2 V or less.

Finally, Table 1 compares the performance of this work with those of various prior low-pass-filters. As there is a lot of figure-of-merit (FoM) definitions, the FoM term is not included in the table. The group delay ripple is the least. The 3rd-order distortions (HD3) seen in Figure 6 and IIP3 are superior to those of other designs, considering that the filter order is as large as 7 and the supply voltage is as low as 1.2 V. The dynamic range is in the same level as those of other

Table 1. Performance comparison of a test chip

| Reference            | [4]                              | [5]                        | [6]                                    | [3]                                      | This Work   |
|----------------------|----------------------------------|----------------------------|--|--|---|
| CMOS Technology      | 0.35um                           | 65nm                       | 0.18um                                 | 0.13um                                   | 65nm  |
| Filter Order         | 7                                | 5                          | 4                                      | 2  | 7   |
| -3dB Frequency       | 200MHz                           | 275MHz                     | 1GHz                                   | 200MHz                                   | 200MHz  |
| Group Delay Ripple   | <4%<br>@fc                       | -                          | <4%<br>@1.5fc                          | -  | <2.2%<br>@fc                                      |
| HD3                  | <-44dB<br>@500mVp-p<br>fin=30MHz | -                          | IM3<br><-43dB<br>@350mVp-p<br>fin=1GHz | IM3<br><-31dB<br>@750mVp-p<br>fin=150MHz | <-55dB<br>@400mVp-p<br>differential<br>fin=100MHz |
| IIP3                 | -                                | -12.5dBV<br>(+0.5dBm)      | -                                      | +14dBm                                   | +10.3dBm  |
| DR                   | 50 dB                            | 44 dB                      | 39 dB                                  | 54.5 dB                                  | 45 dB   |
| Input Referred Noise | 89 nV/ $\sqrt{\text{Hz}}$        | 7.8 nV/ $\sqrt{\text{Hz}}$ | -                                      | 35.4 nV/ $\sqrt{\text{Hz}}$              | 70 nV/ $\sqrt{\text{Hz}}$                         |
| Supply Voltage       | $\pm 1.5$ V                      | 1.2V                       | 1.5V                                   | 1.2V                                     | 1.2V  |
| Power Consumption    | 60mW                             | 36mW                       | 175mW                                  | 20.8mW                                   | 60mW  |

designs except for that of reference 3 with the supply voltage of less than 1.5 V. The noise level is almost the same as that of reference 4, while the supply voltage is almost one-third in our design. Although many resistors are used, the noise level is not large, however, it may become difficult to reduce the noise more. This should be the matter for future study.

## V. CONCLUSION

A high-speed and high-performance analog circuit was realized by applying positive feedbacks and using a 65-nm CMOS with the characteristic of very low output-resistance in a deep-submicron transistor under a low-supply-voltage condition such as 1.2 V.

## ACKNOWLEDGMENT

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